

<b>Notice of References Cited</b>	Application/Control No. 10/533,247	Applicant(s)/Patent Under Reexamination JUNG, II-HYUNG	
	Examiner BINH K. TIEU	Art Unit 2614	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0043754	03-2004	Whewell, Jean E.	455/408
*	C	US-5,995,822	11-1999	Smith et al.	455/406
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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